

<b>Notice of References Cited</b>	Application/Control No. 10/709,893	Applicant(s)/Patent Under Reexamination LIN, AKAN	
	Examiner Pierre-Michel Bataille	Art Unit 2186	Page 1 of 1

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*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-7,100,018	08-2006	Zhang et al.	711/207
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	C	US-			
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**NON-PATENT DOCUMENTS**

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